

Technical !	Technical Data of Crystal Unit				
MURATA Part No	o.: XRCGE	316M000FXN20R0			
Applied t	to TLSR8	267			
Oscillation circuit is con	mpatible to below IC).			
TLSR8262 TLSR8266 TLSR8269 TLSR86xx					

Murata Manufacturing Co., Ltd.



■ Murata's recommendation 推奨回路定数

Item				Condition
IC name		IC名		TLSR8267
Parts Number of		村田品名		XRCGB16M000FXN20R0
Circuit Parameter	External	负载电容	CL1	10pF
	load capacitance	负载电容	CL2	10pF
	Feedback resistance	反馈电阻	Rf	No mount
	Damping resistance	阻尼电阻	Rd	0ohm
Supply Voltage Range 电源电压范围		5V		
Temp. Range		温度范围		-30 to 85deg.C

Test Circuit Set:5V Evaluation board : BLE Xin Xout Rf Rd≷ 卝 VOUT VIN CL1 CL2 +7/1 7/1 7/1

Murata standard Measurement equipment

DSO6052(K) Oscilloscope Current probe Passive probe CT-6(T) P5100A(T) (40Mohm/2.5pF) E3631A(K) DC supply Sepectrum analyzer N9010A(K)

(K) Keysight (T) Tektronix

■ Characteristics of oscillation circuit on above condition 推奨定数での発振回路特性

Circuit Characteristics 特性	Value 測定値			Remarks 備考
Center Frequency and Difference 起振回路上起振频率与偏差量 (*1)	15.999980		[MHz]	Oscillating frequency and its shift against nominal frequency 在起振回路上的频率以及相对于公称频率之间的偏差量
(Typical sample at Vdd=5V,+25deg.C)		-1		
Load Capacitance on your PCB 负载容量值 (Typical sample at Vdd=5V,+25deg.C)	8.2 [pF]		[pF]	This value shows load capacitance the evaluated circuit has 在起振回路上等价于连接在谐振器两端的容量
Negative Resistance and Oscillation margin 负性电阻/起振余裕度 (at Vdd=5V,+25deg.C)	-R	1641	[Ω]	The details is explained in page 2 详细内容参见下页说明
	Ratio	6.1	[Times]	
Drive Level 激励功率 (Typical sample at Vdd=5V,+25deg.C)	53 [uW]		[uW]	Drive power of crystal under circuit condition 起振回路在工作状态下谐振器消耗的功率
Oscillating Voltage 起振电压 (Typical sample at Vdd=5V,+25deg.C)	VINp-p	1.0	[V]	Swing level at input side 输入端起振振幅 (VIN_H - VIN_L)
	VOUTp-p	1.0	[V]	Swing level at output side 输出端起振振幅 (VOUT_H - VOUT_L)
Oscillation Start up Time 启动时间 (*2) (Typical sample at Vdd=5V,+25deg.C)	29.98 [ms		[ms]	The time takes steady amplitude of Vout(Xout) 达到稳定状态振幅所需要时间

- *1 Frequency difference means the oscillating frequency difference between your PCB and Murata's frequency sorting circuit. 频率偏差指在贵公司基板上的测定频率与本公司标准回路上测定频率间的偏差。
 *2 The measurement results is affected by the rise-up characteristics of supplied voltage on your PCB. 测定结果受实装基板上电源启动方式的影响。

The characteristics of the crystal oscillation circuit is affected by the circuit constants and actual mounting conditions and so on.

Therefore, it is possible to get the different results from above one due to the production variation of the crystal oscillator circuitry.

In your company, please use this results after confirmation of the matching between our crystal unit and oscillator circuit.

And furthermore, since the above-mentioned evaluation results evaluate only an oscillating circuit block, please confirm the checking of operations of a set

in your company.

在起事项 起振回路的特性收到回路常数和实装状态等的影响。上述结果由于回路基板的偏差可能会有所不同。 请贵公司在确认水晶谐振器与起振回路的匹配结果后进行使用。同时上述评价结果仅针对于起振回路部分的评价,整块基板的动作请贵公司确认。

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■ Test Data : Characteristics of recommended conditions

Center frequency Center frequency difference

15.999980 MHz

-1 ppm from 16MHz

This frequency difference causes imbalance of initial frequency tolerance on your PCB, because of load capacitance difference.

Load capacitance of the circuit

This value shows load capacitance the evaluated circuit has.

Our crystal proposed in this report is sorted with 8pF as load capacitance

Negative resistance

Ratio of negative resistance |-R| to R1spec.

Ratio 6.1 times

Ratio = |-R| / R1spec.

R| 1640 ohm Negative resistance |-R| = Rs_max + Re

Rs_max: 1500 ohm Maximum series resistance for Crystal Unit to keep oscillation

Re: 140.5 ohm

Effective resistance of Crystal Unit at actual oscillation frequency

R1spec. 270 ohm
Equivalent series resistance

Drive level

Drive power of crystal under circuit condition shown in page 1

Drive level 53 uW

Drive level = $I^2 \times R1$

I: 0.66 mA (RMS) Current through Crystal Unit measured by current probe

123.1 ohm

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